



Mechanical data: $A_x=290\ \mu\text{m}$, $A_y=290\ \mu\text{m}$,
 $B_x=B_y=80\ \mu\text{m}$

Chip thickness: $138\pm 12\ \mu\text{m}$ on 4" wafer

Scribe Line width - 40 μm

Top Metal – Pin 1: Al metallization for wire bonding

Backside – Pin 2: Ti-Ni-Ag for soldering

Probing: sampling testing: no bad dice inking guaranteed good dice quantity $\geq 93\%$

Schematic and pinning diagram

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Peak pulse power	P_{PP}	8/20 μs pulse per diode	100*	W
Peak pulse current	I_{PP}	8/20 μs pulse per diode	5*	A
Electrostatic Discharge	ESD	IEC 61000-4-2, level 4 (ESD)	>15 (air); >8 (contact)	kV
Max.junction temperature	T_j		150	$^{\circ}\text{C}$

Characteristics ($T_a=25^{\circ}\text{C}$)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Reverse Stand-Off Voltage	V_{RWM}		-	-	5.0	V
Reverse leakage current	I_R	$V_R=+5.0\text{V}$	-	-	1.0	μA
Breakdown voltage	V_{BR}	$I=1\text{mA}$	6.0	7.0	-	V
Forward voltage	V_F	$I_F=15\text{mA}$	-	-	1.15	V
Clamping Voltage	V_{CL}	$I_{PP}=1\text{A}$, $t=8/20\ \mu\text{s}$; $I_{PP}=5\text{A}$, $t=8/20\ \mu\text{s}$	-	-	10.0* 20.0*	V
Capacitance	C_j	$V_R=0\text{V}$; $f=1\text{MHz}$	-	0,5	0,7	pF

*- For Device testing